January 2005

# FDW9926NZ

**FAIRCHILD** 

# Common Drain N-Channel 2.5V specified PowerTrench<sup>®</sup> MOSFET

### **General Description**

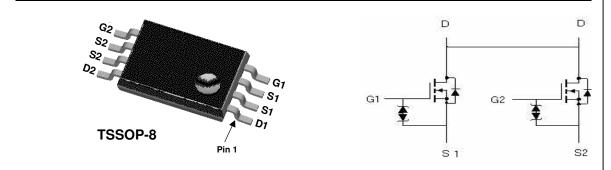
This N-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V - 10V).

## Applications

- Battery protection
- Load switch
- Power management

## Features

- 4.5 A, 20 V.  $R_{DS(ON)} = 32 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$  $R_{DS(ON)} = 45 \text{ m}\Omega @ V_{GS} = 2.5 \text{ V}$
- ESD protection diode (note 3)
- High performance trench technology for extremely low  $R_{DS(ON)}$  @  $V_{GS}$  = 2.5 V
- Low profile TSSOP-8 package



# Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DSS</sub>	Drain-Source	ource Voltage		20	V	
V <sub>GSS</sub>	Gate-Sourc	ource Voltage		±12	V	
ID	Drain Current – Continuous (r		(Note 1a)	4.5	A	
		<ul> <li>Pulsed</li> </ul>		30		
P <sub>D</sub>	Total Power Dissipation		(Note 1a)	1.6	W	
			(Note 1b)	1.1		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C		
Therma	I Charac	teristics				
R <sub>0JA</sub>	Thermal Resistance, Junction-to-Ambient (Note 1a)		ient (Note 1a)	77	°C/W	
				114		
Packag	e Markin	g and Ordering I	nformation			
Device Marking		Device	Reel Size	Tape width	Quantity	
9926NZ		FDW9926NZ	13"	12mm	2500 units	

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
-				176	Мал	onits
	acteristics			r —		
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS}=0~V, \qquad I_{D}=250~\mu A$	20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		15		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 16 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$			1	μA
I <sub>GSS</sub>	Gate-Body Leakage	$V_{\text{GS}}=\pm 12 \text{ V},  V_{\text{DS}}=0 \text{ V}$			±10	μA
On Chara	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	0.6	1	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_{J}}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = 250 µA, Referenced to 25°C		-3.1		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source	$V_{GS} = 4.5 \text{ V},  I_D = 4.5 \text{ A}$		27	32	mΩ
	On-Resistance	$V_{GS} = 2.5 V$ , $I_D = 3.8 A$		38	45	
		$V_{GS} = 4.5 \text{ V}, I_D = 4.5 \text{A}, T_J = 125^{\circ}\text{C}$		36	49	
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{\text{DS}} = 5 \text{ V}, \qquad I_{\text{D}} = 4.5 \text{ A}$		22		S
Dynamic	Characteristics					
Ciss	Input Capacitance	$V_{DS} = 10 V$ , $V_{GS} = 0 V$ ,		600		pF
Coss	Output Capacitance	f = 1.0 MHz		160		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			90		pF
R <sub>G</sub>	Gate Resistance	$V_{GS} = 15 \text{ mV}, \text{ f} = 1.0 \text{ MHz}$		1.4		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn–On Delay Time	$V_{DD} = 10 V$ , $I_D = 1 A$ ,		8	16	ns
t <sub>r</sub>	Turn–On Rise Time	$V_{GS} = 4.5 V$ , $R_{GEN} = 6 \Omega$		8	16	ns
t <sub>d(off)</sub>	Turn–Off Delay Time			14	26	ns
tr	Turn–Off Fall Time			4	8	ns
Qg	Total Gate Charge	$V_{DS} = 10 V$ , $I_D = 4.5 A$ ,		5.7	8	nC
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 4.5 V$		1.3		nC
Q <sub>gd</sub>	Gate–Drain Charge			1.7		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings	•	-		
ls	Maximum Continuous Drain–Sourc	¥			0.83	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \ V, ~~I_S = 0.83 \ A ~~(\text{Note 2})$		0.7	1.2	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 4.5 A,		16		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		5		nC

Notes:

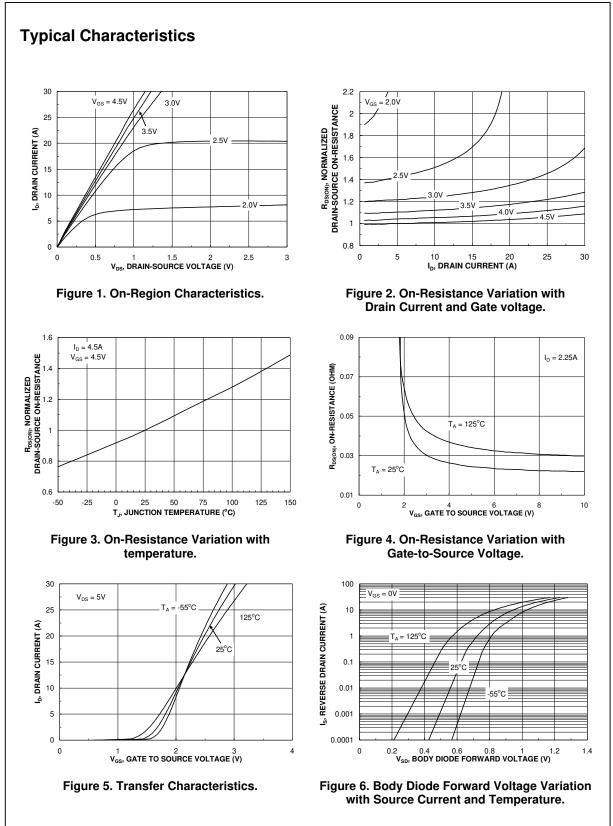
1. R<sub>6JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $\rm R_{\theta JC}$  is guaranteed by design while  $\rm R_{\theta CA}$  is determined by the user's board design.

a) R<sub>θJA</sub> is 77°C/W (steady state) when mounted on a 1 inch<sup>2</sup> copper pad on FR-4.
b) R<sub>θJA</sub> is 114 °C/W (steady state) when mounted on a minimum copper pad on FR-4.

**2.** Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

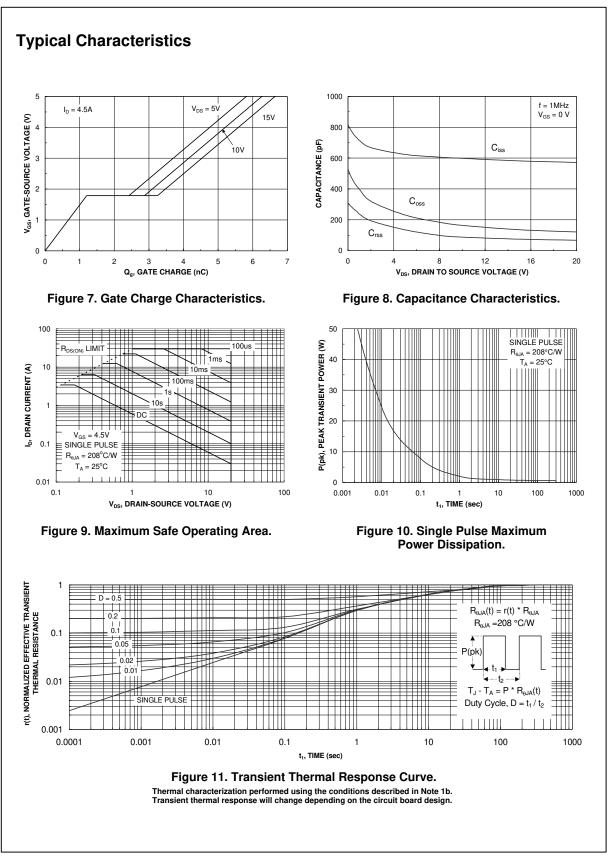
3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# FDW9926NZ



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FDW9926NZ Rev. D(W)



FDW9926NZ

FDW9926NZ Rev. D(W)

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